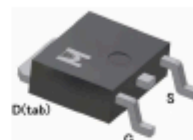
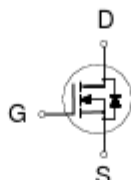


N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	100V
$R_{DS(on)} (MAX.)$	150m Ω
I_D	10A



UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free



ABSOLUTE MAXIMUM RATINGS ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	10	A
	$T_C = 100^\circ\text{C}$		7	
Pulsed Drain Current ¹		I_{DM}	40	
Avalanche Current		I_{AS}	12	
Avalanche Energy	$L = 0.1\text{mH}$, $I_D = 12\text{A}$, $R_G = 25\Omega$	E_{AS}	7.2	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	3.6	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	30	W
	$T_C = 100^\circ\text{C}$		12	
Operating Junction & Storage Temperature Range		T_{Jr} , T_{stg}	-55 to 150	$^\circ\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		4.2	$^\circ\text{C} / \text{W}$
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$